ABSTRACT

PECULIARITIES OF THE ANALYSIS OF THE FORM OF PROFILES X-RAY DIFFRACTION LINES FOR CARBON MATERIALS. PART II. RELATION OF THE FORM OF PROFILES AND DISTRIBUTION OF CRYSTALS ON THE SIZES

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In result of computer simulation of x-ray diffraction maxima 002 carbon materials is established, that the asymmetry of diffraction lines is caused by dependence of interlayer spacings on the sizes of crystals. The correct analysis of the form of x-ray diffraction maxima of carbon materials should consist in a finding of function of distribution of crystals on the sizes.

Key Words: carbon materials, crystal structure, X–ray analysis, computer simulation **Pages** — 8, **figures** — 6, **table** — 2.